

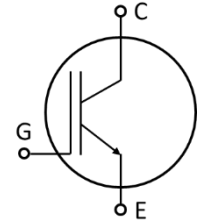
IGBT Chip

Features:

- 1200V Trench & Field stop technology
- Low switching losses
- Positive temperature coefficient
- Easy paralleling

Applications:

- Energy storage inverter
- Uninterruptible power supplies
- Solar inverters



Mechanical parameters

Die size	6.80 × 11.00	mm ²
Emitter pad size	See chip drawing	
Gate pad size	0.63 × 0.35	
Area total	74.80	
Thickness	110	μm
Wafer size	200	mm
Max. possible chips per wafer	345	
Passivation front side	Polyimide	
Pad metal	AlCu with Ti/TiN (5μm & 200A/700A)	
Backside metal	Al/Ti/Ni/Ag	

Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-Emitter voltage	V _{CE}	1200	V
DC collector current	I _C	120	A
Operating junction temperature	T _{vj}	-40 ... +175	°C
Gate emitter voltage	V _{GE}	±20	V

Static Characteristics (tested on wafer), $T_{vj}=25^{\circ}\text{C}$

Parameter	Symbol	Conditions	Value			Unit
			Min.	Typ.	Max.	
Collector-Emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE}=0\text{V}, I_C=1\text{mA}$	1200			V
Collector-Emitter saturation voltage	V_{CESat}	$V_{GE}=15\text{V}, I_C=120\text{A}$		1.88	2.28	
Gate-Emitter threshold voltage	$V_{GE(th)}$	$I_C=2.34\text{mA}, V_{GE}=V_{CE}$	5.23	5.83	6.43	
Zero gate voltage collector current	I_{CES}	$V_{CE}=1200\text{V}, V_{GE}=0\text{V}$			10	μA
Gate-Emitter leakage current	I_{GES}	$V_{CE}=0\text{V}, V_{GE}=20\text{V}$			100	nA
Integrated gate resistor	$r_G^{a)}$			N/A		Ω
Input capacitance	$C_{ies}^{a)}$	$V_{CE}=25\text{V}, V_{GE}=0\text{V},$		17.07		nF
Reverse transfer capacitance	$C_{res}^{a)}$	$f=100\text{kHz}$		0.13		

^{a)} tested on device

Further Electrical Characteristic

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

Application example	SD120R12I7HQ
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Chip Drawing

Note: all dimension are shown in μm

